Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/747,805	NARENDRA ET AL.
Examiner	Art Unit
Thien F. Tran	2811

Thien F. Tran

	SEARCHED					
Class	Subclass	Date	Examiner			
257	706, 707 717, 719 778	3/18/2006	π			
			-			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Interference search history printout	3/18/2006	П			